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Understanding **Embedded - FPGAs (Field Programmable Gate Array)**

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications,

Details

Product Status	Active
Number of LABs/CLBs	1175
Number of Logic Elements/Cells	9400
Total RAM Bits	442368
Number of I/O	384
Number of Gates	-
Voltage - Supply	2.375V ~ 3.465V
Mounting Type	Surface Mount
Operating Temperature	-40°C ~ 100°C (TJ)
Package / Case	484-LFBGA
Supplier Device Package	484-CABGA (19x19)
Purchase URL	https://www.e-xfl.com/product-detail/lattice-semiconductor/lcmxo3lf-9400c-6bg484i

Features

■ Solutions

- Smallest footprint, lowest power, high data throughput bridging solutions for mobile applications
- Optimized footprint, logic density, IO count, IO performance devices for IO management and logic applications
- High IO/logic, lowest cost/IO, high IO devices for IO expansion applications

■ Flexible Architecture

- Logic Density ranging from 640 to 9.4K LUT4
- High IO to LUT ratio with up to 384 IO pins

■ Advanced Packaging

- 0.4 mm pitch: 1K to 4K densities in very small footprint WLCSP (2.5 mm x 2.5 mm to 3.8 mm x 3.8 mm) with 28 to 63 IOs
- 0.5 mm pitch: 640 to 6.9K LUT densities in 6 mm x 6 mm to 10 mm x 10 mm BGA packages with up to 281 IOs
- 0.8 mm pitch: 1K to 9.4K densities with up to 384 IOs in BGA packages

■ Pre-Engineered Source Synchronous I/O

- DDR registers in I/O cells
- Dedicated gearing logic
- 7:1 Gearing for Display I/Os
- Generic DDR, DDRx2, DDRx4

■ High Performance, Flexible I/O Buffer

- Programmable sysIO™ buffer supports wide range of interfaces:
 - LVCMOS 3.3/2.5/1.8/1.5/1.2
 - LVTTTL
 - LVDS, Bus-LVDS, MLVDS, LVPECL
 - MIPI D-PHY Emulated
 - Schmitt trigger inputs, up to 0.5 V hysteresis
- Ideal for IO bridging applications
- I/Os support hot socketing
- On-chip differential termination
- Programmable pull-up or pull-down mode

■ Flexible On-Chip Clocking

- Eight primary clocks
- Up to two edge clocks for high-speed I/O interfaces (top and bottom sides only)
- Up to two analog PLLs per device with fractional-n frequency synthesis
 - Wide input frequency range (7 MHz to 400 MHz)

■ Non-volatile, Multi-time Programmable

- Instant-on
 - Powers up in microseconds
- Optional dual boot with external SPI memory
- Single-chip, secure solution
- Programmable through JTAG, SPI or I²C
- MachXO3L includes multi-time programmable NVCM
- MachXO3LF infinitely reconfigurable Flash
 - Supports background programming of non-volatile memory

■ TransFR Reconfiguration

- In-field logic update while IO holds the system state

■ Enhanced System Level Support

- On-chip hardened functions: SPI, I²C, timer/counter
- On-chip oscillator with 5.5% accuracy
- Unique TraceID for system tracking
- Single power supply with extended operating range
- IEEE Standard 1149.1 boundary scan
- IEEE 1532 compliant in-system programming

■ Applications

- Consumer Electronics
- Compute and Storage
- Wireless Communications
- Industrial Control Systems
- Automotive System

■ Low Cost Migration Path

- Migration from the Flash based MachXO3LF to the NVCM based MachXO3L
- Pin compatible and equivalent timing

Table 2-4. PLL Signal Descriptions (Continued)

Port Name	I/O	Description
CLKOP	O	Primary PLL output clock (with phase shift adjustment)
CLKOS	O	Secondary PLL output clock (with phase shift adjust)
CLKOS2	O	Secondary PLL output clock2 (with phase shift adjust)
CLKOS3	O	Secondary PLL output clock3 (with phase shift adjust)
LOCK	O	PLL LOCK, asynchronous signal. Active high indicates PLL is locked to input and feedback signals.
DPHSRC	O	Dynamic Phase source – ports or WISHBONE is active
STDBY	I	Standby signal to power down the PLL
RST	I	PLL reset without resetting the M-divider. Active high reset.
RESETM	I	PLL reset - includes resetting the M-divider. Active high reset.
RESETC	I	Reset for CLKOS2 output divider only. Active high reset.
RESETD	I	Reset for CLKOS3 output divider only. Active high reset.
ENCLKOP	I	Enable PLL output CLKOP
ENCLKOS	I	Enable PLL output CLKOS when port is active
ENCLKOS2	I	Enable PLL output CLKOS2 when port is active
ENCLKOS3	I	Enable PLL output CLKOS3 when port is active
PLLCLK	I	PLL data bus clock input signal
PLL_RST	I	PLL data bus reset. This resets only the data bus not any register values.
PLLSTB	I	PLL data bus strobe signal
PLLWE	I	PLL data bus write enable signal
PLLADDR [4:0]	I	PLL data bus address
PLLDAT1 [7:0]	I	PLL data bus data input
PLLDATO [7:0]	O	PLL data bus data output
PLLACK	O	PLL data bus acknowledge signal

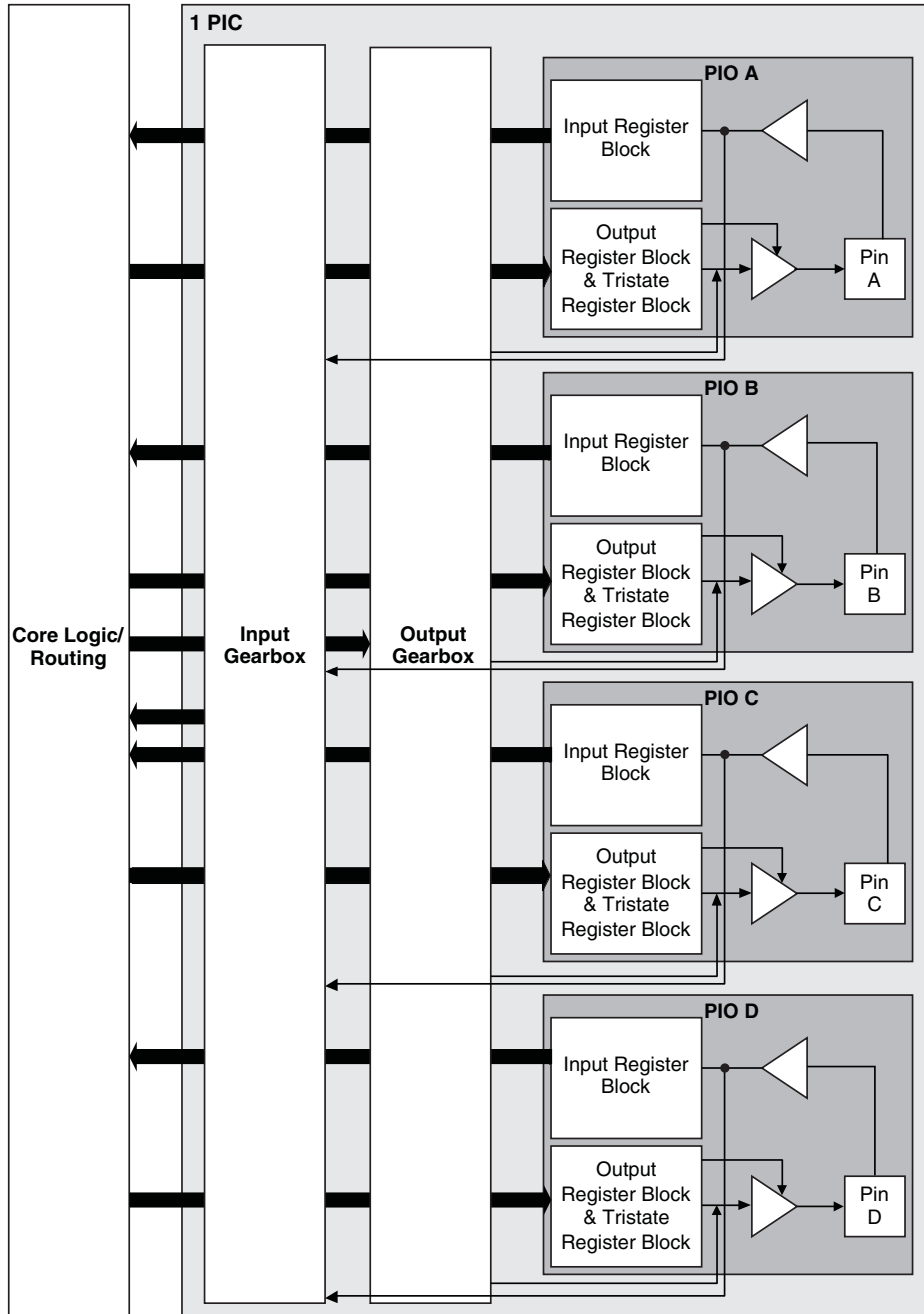
sysMEM Embedded Block RAM Memory

The MachXO3L/LF devices contain sysMEM Embedded Block RAMs (EBRs). The EBR consists of a 9-Kbit RAM, with dedicated input and output registers. This memory can be used for a wide variety of purposes including data buffering, PROM for the soft processor and FIFO.

sysMEM Memory Block

The sysMEM block can implement single port, dual port, pseudo dual port, or FIFO memories. Each block can be used in a variety of depths and widths as shown in Table 2-5.

Figure 2-11. Group of Four Programmable I/O Cells



PIO

The PIO contains three blocks: an input register block, output register block and tri-state register block. These blocks contain registers for operating in a variety of modes along with the necessary clock and selection logic.

Table 2-8. PIO Signal List

Pin Name	I/O Type	Description
CE	Input	Clock Enable
D	Input	Pin input from sysIO buffer.
INDD	Output	Register bypassed input.
INCK	Output	Clock input
Q0	Output	DDR positive edge input
Q1	Output	Registered input/DDR negative edge input
D0	Input	Output signal from the core (SDR and DDR)
D1	Input	Output signal from the core (DDR)
TD	Input	Tri-state signal from the core
Q	Output	Data output signals to sysIO Buffer
TQ	Output	Tri-state output signals to sysIO Buffer
SCLK	Input	System clock for input and output/tri-state blocks.
RST	Input	Local set reset signal

Input Register Block

The input register blocks for the PIOs on all edges contain delay elements and registers that can be used to condition high-speed interface signals before they are passed to the device core.

Left, Top, Bottom Edges

Input signals are fed from the sysIO buffer to the input register block (as signal D). If desired, the input signal can bypass the register and delay elements and be used directly as a combinatorial signal (INDD), and a clock (INCK). If an input delay is desired, users can select a fixed delay. I/Os on the bottom edge also have a dynamic delay, DEL[4:0]. The delay, if selected, reduces input register hold time requirements when using a global clock. The input block allows two modes of operation. In single data rate (SDR) the data is registered with the system clock (SCLK) by one of the registers in the single data rate sync register block. In Generic DDR mode, two registers are used to sample the data on the positive and negative edges of the system clock (SCLK) signal, creating two data streams.

Input Gearbox

Each PIC on the bottom edge has a built-in 1:8 input gearbox. Each of these input gearboxes may be programmed as a 1:7 de-serializer or as one IDDRX4 (1:8) gearbox or as two IDDRX2 (1:4) gearboxes. Table 2-9 shows the gearbox signals.

Table 2-9. Input Gearbox Signal List

Name	I/O Type	Description
D	Input	High-speed data input after programmable delay in PIO A input register block
ALIGNWD	Input	Data alignment signal from device core
SCLK	Input	Slow-speed system clock
ECLK[1:0]	Input	High-speed edge clock
RST	Input	Reset
Q[7:0]	Output	Low-speed data to device core: Video RX(1:7): Q[6:0] GDDR4(1:8): Q[7:0] GDDR2(1:4)(IOL-A): Q4, Q5, Q6, Q7 GDDR2(1:4)(IOL-C): Q0, Q1, Q2, Q3

These gearboxes have three stage pipeline registers. The first stage registers sample the high-speed input data by the high-speed edge clock on its rising and falling edges. The second stage registers perform data alignment based on the control signals UPDATE and SEL0 from the control block. The third stage pipeline registers pass the data to the device core synchronized to the low-speed system clock. Figure 2-13 shows a block diagram of the input gearbox.

sysIO Buffer

Each I/O is associated with a flexible buffer referred to as a sysIO buffer. These buffers are arranged around the periphery of the device in groups referred to as banks. The sysIO buffers allow users to implement a wide variety of standards that are found in today's systems including LVCMOS, TTL, PCI, LVDS, BLVDS, MLVDS and LVPECL.

Each bank is capable of supporting multiple I/O standards. In the MachXO3L/LF devices, single-ended output buffers, ratioed input buffers (LVTTL, LVCMOS and PCI), differential (LVDS) input buffers are powered using I/O supply voltage (V_{CCIO}). Each sysIO bank has its own V_{CCIO} .

MachXO3L/LF devices contain three types of sysIO buffer pairs.

1. Left and Right sysIO Buffer Pairs

The sysIO buffer pairs in the left and right banks of the device consist of two single-ended output drivers and two single-ended input buffers (for ratioed inputs such as LVCMOS and LVTTL). The I/O pairs on the left and right of the devices also have differential input buffers.

2. Bottom sysIO Buffer Pairs

The sysIO buffer pairs in the bottom bank of the device consist of two single-ended output drivers and two single-ended input buffers (for ratioed inputs such as LVCMOS and LVTTL). The I/O pairs on the bottom also have differential input buffers. Only the I/Os on the bottom banks have programmable PCI clamps and differential input termination. The PCI clamp is enabled after V_{CC} and V_{CCIO} are at valid operating levels and the device has been configured.

3. Top sysIO Buffer Pairs

The sysIO buffer pairs in the top bank of the device consist of two single-ended output drivers and two single-ended input buffers (for ratioed inputs such as LVCMOS and LVTTL). The I/O pairs on the top also have differential I/O buffers. Half of the sysIO buffer pairs on the top edge have true differential outputs. The sysIO buffer pair comprising of the A and B PIOs in every PIC on the top edge have a differential output driver.

Typical I/O Behavior During Power-up

The internal power-on-reset (POR) signal is deactivated when V_{CC} and V_{CCIO0} have reached V_{PORUP} level defined in the Power-On-Reset Voltage table in the DC and Switching Characteristics section of this data sheet. After the POR signal is deactivated, the FPGA core logic becomes active. It is the user's responsibility to ensure that all V_{CCIO} banks are active with valid input logic levels to properly control the output logic states of all the I/O banks that are critical to the application. The default configuration of the I/O pins in a blank device is tri-state with a weak pull-down to GND (some pins such as PROGRAMN and the JTAG pins have weak pull-up to V_{CCIO} as the default functionality). The I/O pins will maintain the blank configuration until V_{CC} and V_{CCIO} (for I/O banks containing configuration I/Os) have reached V_{PORUP} levels at which time the I/Os will take on the user-configured settings only after a proper download/configuration.

There are various ways a user can ensure that there are no spurious signals on critical outputs as the device powers up. These are discussed in more detail in TN1280, [MachXO3 sysIO Usage Guide](#).

Supported Standards

The MachXO3L/LF sysIO buffer supports both single-ended and differential standards. Single-ended standards can be further subdivided into LVCMOS, LVTTL, and PCI. The buffer supports the LVTTL, PCI, LVCMOS 1.2 V, 1.5 V, 1.8 V, 2.5 V, and 3.3 V standards. In the LVCMOS and LVTTL modes, the buffer has individually configurable options for drive strength, bus maintenance (weak pull-up, weak pull-down, bus-keeper latch or none) and open drain. BLVDS, MLVDS and LVPECL output emulation is supported on all devices. The MachXO3L/LF devices support on-chip LVDS output buffers on approximately 50% of the I/Os on the top bank. Differential receivers for LVDS, BLVDS, MLVDS and LVPECL are supported on all banks of MachXO3L/LF devices. PCI support is provided in the bottom bank of the MachXO3L/LF devices. Table 2-11 summarizes the I/O characteristics of the MachXO3L/LF PLDs.

Configuration and Testing

This section describes the configuration and testing features of the MachXO3L/LF family.

IEEE 1149.1-Compliant Boundary Scan Testability

All MachXO3L/LF devices have boundary scan cells that are accessed through an IEEE 1149.1 compliant test access port (TAP). This allows functional testing of the circuit board, on which the device is mounted, through a serial scan path that can access all critical logic nodes. Internal registers are linked internally, allowing test data to be shifted in and loaded directly onto test nodes, or test data to be captured and shifted out for verification. The test access port consists of dedicated I/Os: TDI, TDO, TCK and TMS. The test access port shares its power supply with V_{CCIO} Bank 0 and can operate with LVCMOS3.3, 2.5, 1.8, 1.5, and 1.2 standards.

For more details on boundary scan test, see AN8066, [Boundary Scan Testability with Lattice sysIO Capability](#) and TN1087, [Minimizing System Interruption During Configuration Using TransFR Technology](#).

Device Configuration

All MachXO3L/LF devices contain two ports that can be used for device configuration. The Test Access Port (TAP), which supports bit-wide configuration and the sysCONFIG port which supports serial configuration through I²C or SPI. The TAP supports both the IEEE Standard 1149.1 Boundary Scan specification and the IEEE Standard 1532 In-System Configuration specification. There are various ways to configure a MachXO3L/LF device:

1. Internal NVCM/Flash Download
2. JTAG
3. Standard Serial Peripheral Interface (Master SPI mode) – interface to boot PROM memory
4. System microprocessor to drive a serial slave SPI port (SSPI mode)
5. Standard I²C Interface to system microprocessor

Upon power-up, the configuration SRAM is ready to be configured using the selected sysCONFIG port. Once a configuration port is selected, it will remain active throughout that configuration cycle. The IEEE 1149.1 port can be activated any time after power-up by sending the appropriate command through the TAP port. Optionally the device can run a CRC check upon entering the user mode. This will ensure that the device was configured correctly.

The sysCONFIG port has 10 dual-function pins which can be used as general purpose I/Os if they are not required for configuration. See TN1279, [MachXO3 Programming and Configuration Usage Guide](#) for more information about using the dual-use pins as general purpose I/Os.

Lattice design software uses proprietary compression technology to compress bit-streams for use in MachXO3L/LF devices. Use of this technology allows Lattice to provide a lower cost solution. In the unlikely event that this technology is unable to compress bitstreams to fit into the amount of on-chip NVCM/Flash, there are a variety of techniques that can be utilized to allow the bitstream to fit in the on-chip NVCM/Flash. For more details, refer to TN1279, [MachXO3 Programming and Configuration Usage Guide](#).

The Test Access Port (TAP) has five dual purpose pins (TDI, TDO, TMS, TCK and JTAGENB). These pins are dual function pins - TDI, TDO, TMS and TCK can be used as general purpose I/O if desired. For more details, refer to TN1279, [MachXO3 Programming and Configuration Usage Guide](#).

TransFR (Transparent Field Reconfiguration)

TransFR is a unique Lattice technology that allows users to update their logic in the field without interrupting system operation using a simple push-button solution. For more details refer to TN1087, [Minimizing System Interruption During Configuration Using TransFR Technology](#) for details.

Security and One-Time Programmable Mode (OTP)

For applications where security is important, the lack of an external bitstream provides a solution that is inherently more secure than SRAM-based FPGAs. This is further enhanced by device locking. MachXO3L/LF devices contain security bits that, when set, prevent the readback of the SRAM configuration and NVCM/Flash spaces. The device can be in one of two modes:

1. Unlocked – Readback of the SRAM configuration and NVCM/Flash spaces is allowed.
2. Permanently Locked – The device is permanently locked.

Once set, the only way to clear the security bits is to erase the device. To further complement the security of the device, a One Time Programmable (OTP) mode is available. Once the device is set in this mode it is not possible to erase or re-program the NVCM/Flash and SRAM OTP portions of the device. For more details, refer to TN1279, [MachXO3 Programming and Configuration Usage Guide](#).

Password

The MachXO3LF supports a password-based security access feature also known as Flash Protect Key. Optionally, the MachXO3L device can be ordered with a custom specification (c-spec) to support this feature. The Flash Protect Key feature provides a method of controlling access to the Configuration and Programming modes of the device. When enabled, the Configuration and Programming edit mode operations (including Write, Verify and Erase operations) are allowed only when coupled with a Flash Protect Key which matches that expected by the device. Without a valid Flash Protect Key, the user can perform only rudimentary non-configuration operations such as Read Device ID. For more details, refer to TN1313, [Using Password Security with MachXO3 Devices](#).

Dual Boot

MachXO3L/LF devices can optionally boot from two patterns, a primary bitstream and a golden bitstream. If the primary bitstream is found to be corrupt while being downloaded into the SRAM, the device shall then automatically re-boot from the golden bitstream. Note that the primary bitstream must reside in the external SPI Flash. The golden image MUST reside in an on-chip NVCM/Flash. For more details, refer to TN1279, [MachXO3 Programming and Configuration Usage Guide](#).

Soft Error Detection

The SED feature is a CRC check of the SRAM cells after the device is configured. This check ensures that the SRAM cells were configured successfully. This feature is enabled by a configuration bit option. The Soft Error Detection can also be initiated in user mode via an input to the fabric. The clock for the Soft Error Detection circuit is generated using a dedicated divider. The undivided clock from the on-chip oscillator is the input to this divider. For low power applications users can switch off the Soft Error Detection circuit. For more details, refer to TN1292, [MachXO3 Soft Error Detection Usage Guide](#).

Soft Error Correction

The MachXO3LF device supports Soft Error Correction (SEC). Optionally, the MachXO3L device can be ordered with a custom specification (c-spec) to support this feature. When BACKGROUND_RECONFIG is enabled using the Lattice Diamond Software in a design, asserting the PROGRAMN pin or issuing the REFRESH sysConfig command refreshes the SRAM array from configuration memory. Only the detected error bit is corrected. No other SRAM cells are changed, allowing the user design to function uninterrupted.

During the project design phase, if the overall system cannot guarantee containment of the error or its subsequent effects on downstream data or control paths, Lattice recommends using SED only. The MachXO3 can be then be soft-reset by asserting PROGRAMN or issuing the Refresh command over a sysConfig port in response to SED. Soft-reset additionally erases the SRAM array prior to the SRAM refresh, and asserts internal Reset circuitry to guarantee a known state. For more details, refer to TN1292, [MachXO3 Soft Error Detection \(SED\)/Correction \(SEC\) Usage Guide](#).

Absolute Maximum Ratings^{1, 2, 3}

	MachXO3L/LF E (1.2 V)	MachXO3L/LF C (2.5 V/3.3 V)
Supply Voltage V_{CC}	-0.5 V to 1.32 V	-0.5 V to 3.75 V
Output Supply Voltage V_{CCIO}	-0.5 V to 3.75 V	-0.5 V to 3.75 V
I/O Tri-state Voltage Applied ^{4, 5}	-0.5 V to 3.75 V	-0.5 V to 3.75 V
Dedicated Input Voltage Applied ⁴	-0.5 V to 3.75 V	-0.5 V to 3.75 V
Storage Temperature (Ambient)	-55 °C to 125 °C	-55 °C to 125 °C
Junction Temperature (T_J)	-40 °C to 125 °C	-40 °C to 125 °C

1. Stress above those listed under the “Absolute Maximum Ratings” may cause permanent damage to the device. Functional operation of the device at these or any other conditions above those indicated in the operational sections of this specification is not implied.
2. Compliance with the Lattice [Thermal Management](#) document is required.
3. All voltages referenced to GND.
4. Overshoot and undershoot of -2 V to ($V_{IHMAX} + 2$) volts is permitted for a duration of <20 ns.
5. The dual function I²C pins SCL and SDA are limited to -0.25 V to 3.75 V or to -0.3 V with a duration of <20 ns.

Recommended Operating Conditions¹

Symbol	Parameter	Min.	Max.	Units
V_{CC}^1	Core Supply Voltage for 1.2 V Devices	1.14	1.26	V
	Core Supply Voltage for 2.5 V/3.3 V Devices	2.375	3.465	V
$V_{CCIO}^{1, 2, 3}$	I/O Driver Supply Voltage	1.14	3.465	V
t_{JCOM}	Junction Temperature Commercial Operation	0	85	°C
t_{JIND}	Junction Temperature Industrial Operation	-40	100	°C

1. Like power supplies must be tied together. For example, if V_{CCIO} and V_{CC} are both the same voltage, they must also be the same supply.
2. See recommended voltages by I/O standard in subsequent table.
3. V_{CCIO} pins of unused I/O banks should be connected to the V_{CC} power supply on boards.

Power Supply Ramp Rates¹

Symbol	Parameter	Min.	Typ.	Max.	Units
t_{RAMP}	Power supply ramp rates for all power supplies.	0.01	—	100	V/ms

1. Assumes monotonic ramp rates.

Power-On-Reset Voltage Levels^{1, 2, 3, 4, 5}

Symbol	Parameter	Min.	Typ.	Max.	Units
V _{PORUP}	Power-On-Reset ramp up trip point (band gap based circuit monitoring V _{CCINT} and V _{CCIO0})	0.9	—	1.06	V
V _{PORUPEXT}	Power-On-Reset ramp up trip point (band gap based circuit monitoring external V _{CC} power supply)	1.5	—	2.1	V
V _{PORDNBG}	Power-On-Reset ramp down trip point (band gap based circuit monitoring V _{CCINT})	0.75	—	0.93	V
V _{PORDNBGEXT}	Power-On-Reset ramp down trip point (band gap based circuit monitoring V _{CC})	0.98	—	1.33	V
V _{PORDNSRAM}	Power-On-Reset ramp down trip point (SRAM based circuit monitoring V _{CCINT})	—	0.6	—	V
V _{PORDNSRAMEXT}	Power-On-Reset ramp down trip point (SRAM based circuit monitoring V _{CC})	—	0.96	—	V

1. These POR trip points are only provided for guidance. Device operation is only characterized for power supply voltages specified under recommended operating conditions.
2. For devices without voltage regulators V_{CCINT} is the same as the V_{CC} supply voltage. For devices with voltage regulators, V_{CCINT} is regulated from the V_{CC} supply voltage.
3. Note that V_{PORUP} (min.) and V_{PORDNBG} (max.) are in different process corners. For any given process corner V_{PORDNBG} (max.) is always 12.0 mV below V_{PORUP} (min.).
4. V_{PORUPEXT} is for C devices only. In these devices a separate POR circuit monitors the external V_{CC} power supply.
5. V_{CCIO0} does not have a Power-On-Reset ramp down trip point. V_{CCIO0} must remain within the Recommended Operating Conditions to ensure proper operation.

Hot Socketing Specifications^{1, 2, 3}

Symbol	Parameter	Condition	Max.	Units
I _{DK}	Input or I/O leakage Current	0 < V _{IN} < V _{IH} (MAX)	+/-1000	μA

1. Insensitive to sequence of V_{CC} and V_{CCIO}. However, assumes monotonic rise/fall rates for V_{CC} and V_{CCIO}.
2. 0 < V_{CC} < V_{CC} (MAX), 0 < V_{CCIO} < V_{CCIO} (MAX).
3. I_{DK} is additive to I_{PU}, I_{PD} or I_{BH}.

ESD Performance

Please refer to the [MachXO2 Product Family Qualification Summary](#) for complete qualification data, including ESD performance.

Programming and Erase Supply Current – C/E Devices^{1, 2, 3, 4}

Symbol	Parameter	Device	Typ. ⁴	Units
I _{CC}	Core Power Supply	LCMXO3L/LF-1300C 256 Ball Package	22.1	mA
		LCMXO3L/LF-2100C	22.1	mA
		LCMXO3L/LF-2100C 324 Ball Package	26.8	mA
		LCMXO3L/LF-4300C	26.8	mA
		LCMXO3L/LF-4300C 400 Ball Package	33.2	mA
		LCMXO3L/LF-6900C	33.2	mA
		LCMXO3L/LF-9400C	39.6	mA
		LCMXO3L/LF-640E	17.7	mA
		LCMXO3L/LF-1300E	17.7	mA
		LCMXO3L/LF-1300E 256 Ball Package	18.3	mA
		LCMXO3L/LF-2100E	18.3	mA
		LCMXO3L/LF-2100E 324 Ball Package	20.4	mA
		LCMXO3L/LF-4300E	20.4	mA
		LCMXO3L/LF-6900E	23.9	mA
		LCMXO3L/LF-9400E	28.5	mA
I _{CCIO}	Bank Power Supply ⁵ V _{CCIO} = 2.5 V	All devices	0	mA

1. For further information on supply current, please refer to TN1289, [Power Estimation and Management for MachXO3 Devices](#).
2. Assumes all inputs are held at V_{CCIO} or GND and all outputs are tri-stated.
3. Typical user pattern.
4. JTAG programming is at 25 MHz.
5. T_J = 25 °C, power supplies at nominal voltage.
6. Per bank. V_{CCIO} = 2.5 V. Does not include pull-up/pull-down.

sysIO Recommended Operating Conditions

Standard	V _{CCIO} (V)			V _{REF} (V)		
	Min.	Typ.	Max.	Min.	Typ.	Max.
LVC MOS 3.3	3.135	3.3	3.465	—	—	—
LVC MOS 2.5	2.375	2.5	2.625	—	—	—
LVC MOS 1.8	1.71	1.8	1.89	—	—	—
LVC MOS 1.5	1.425	1.5	1.575	—	—	—
LVC MOS 1.2	1.14	1.2	1.26	—	—	—
LV TTL	3.135	3.3	3.465	—	—	—
LVDS25 ^{1,2}	2.375	2.5	2.625	—	—	—
LVDS33 ^{1,2}	3.135	3.3	3.465	—	—	—
LVPECL ¹	3.135	3.3	3.465	—	—	—
BLVDS ¹	2.375	2.5	2.625	—	—	—
MIPI ³	2.375	2.5	2.625	—	—	—
MIPI_LP ³	1.14	1.2	1.26	—	—	—
LVC MOS25R33	3.135	3.3	3.6	1.1	1.25	1.4
LVC MOS18R33	3.135	3.3	3.6	0.75	0.9	1.05
LVC MOS18R25	2.375	2.5	2.625	0.75	0.9	1.05
LVC MOS15R33	3.135	3.3	3.6	0.6	0.75	0.9
LVC MOS15R25	2.375	2.5	2.625	0.6	0.75	0.9
LVC MOS12R33 ⁴	3.135	3.3	3.6	0.45	0.6	0.75
LVC MOS12R25 ⁴	2.375	2.5	2.625	0.45	0.6	0.75
LVC MOS10R33 ⁴	3.135	3.3	3.6	0.35	0.5	0.65
LVC MOS10R25 ⁴	2.375	2.5	2.625	0.35	0.5	0.65

1. Inputs on-chip. Outputs are implemented with the addition of external resistors.
2. For the dedicated LVDS buffers.
3. Requires the addition of external resistors.
4. Supported only for inputs and BIDs for -6 speed grade devices.

BLVDS

The MachXO3L/LF family supports the BLVDS standard through emulation. The output is emulated using complementary LVCMOS outputs in conjunction with resistors across the driver outputs. The input standard is supported by the LVDS differential input buffer. BLVDS is intended for use when multi-drop and bi-directional multi-point differential signaling is required. The scheme shown in Figure 3-2 is one possible solution for bi-directional multi-point differential signals.

Figure 3-2. BLVDS Multi-point Output Example

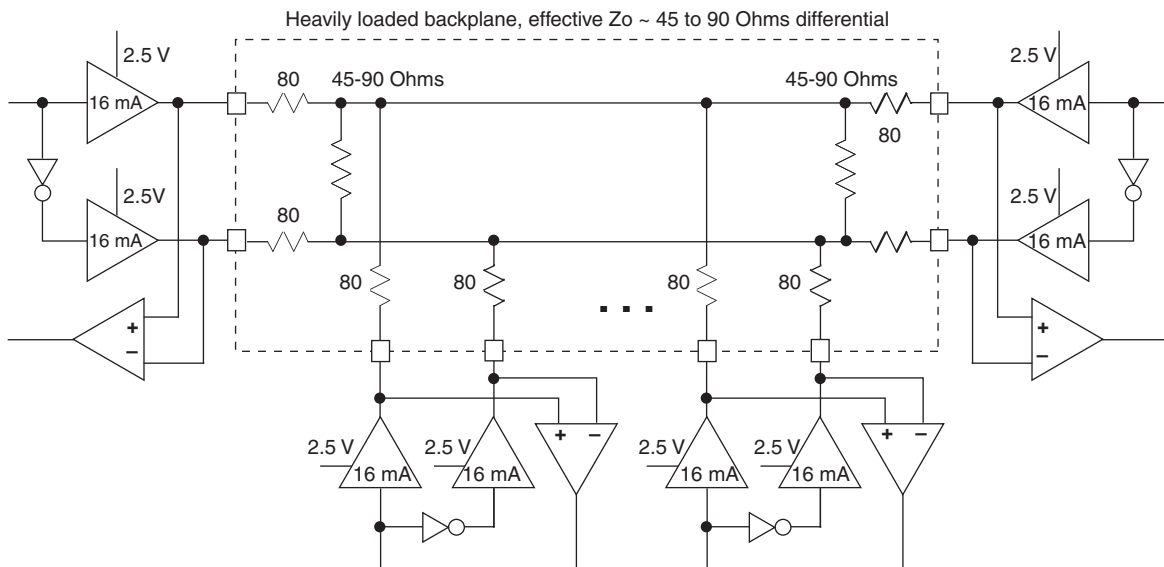


Table 3-2. BLVDS DC Conditions¹

Over Recommended Operating Conditions

Symbol	Description	Nominal		Units
		Z _o = 45	Z _o = 90	
Z _{OUT}	Output impedance	20	20	Ohms
R _S	Driver series resistance	80	80	Ohms
R _{TLEFT}	Left end termination	45	90	Ohms
R _{TRIGHT}	Right end termination	45	90	Ohms
V _{OH}	Output high voltage	1.376	1.480	V
V _{OL}	Output low voltage	1.124	1.020	V
V _{OD}	Output differential voltage	0.253	0.459	V
V _{CM}	Output common mode voltage	1.250	1.250	V
I _{DC}	DC output current	11.236	10.204	mA

1. For input buffer, see LVDS table.

LVPECL

The MachXO3L/LF family supports the differential LVPECL standard through emulation. This output standard is emulated using complementary LVCMOS outputs in conjunction with resistors across the driver outputs on all the devices. The LVPECL input standard is supported by the LVDS differential input buffer. The scheme shown in Differential LVPECL is one possible solution for point-to-point signals.

Figure 3-3. Differential LVPECL

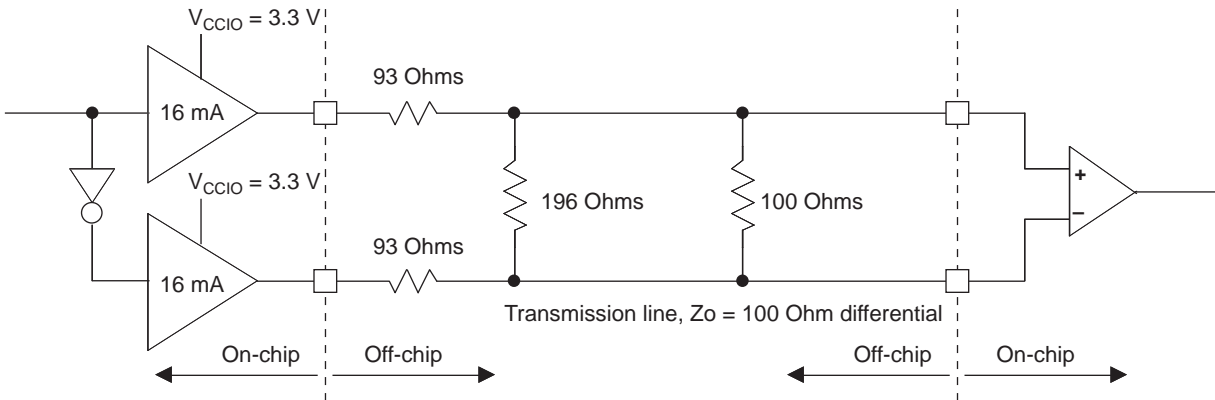


Table 3-3. LVPECL DC Conditions¹

Over Recommended Operating Conditions

Symbol	Description	Nominal	Units
Z_{OUT}	Output impedance	20	Ohms
R_S	Driver series resistor	93	Ohms
R_P	Driver parallel resistor	196	Ohms
R_T	Receiver termination	100	Ohms
V_{OH}	Output high voltage	2.05	V
V_{OL}	Output low voltage	1.25	V
V_{OD}	Output differential voltage	0.80	V
V_{CM}	Output common mode voltage	1.65	V
Z_{BACK}	Back impedance	100.5	Ohms
I_{DC}	DC output current	12.11	mA

1. For input buffer, see LVDS table.

For further information on LVPECL, BLVDS and other differential interfaces please see details of additional technical documentation at the end of the data sheet.

MachXO3L/LF External Switching Characteristics – C/E Devices^{1, 2, 3, 4, 5, 6, 10}
Over Recommended Operating Conditions

Parameter	Description	Device	-6		-5		Units
			Min.	Max.	Min.	Max.	
Clocks							
Primary Clocks							
$f_{MAX_PRI}^7$	Frequency for Primary Clock Tree	All MachXO3L/LF devices	—	388	—	323	MHz
t_{W_PRI}	Clock Pulse Width for Primary Clock	All MachXO3L/LF devices	0.5	—	0.6	—	ns
t_{SKEW_PRI}	Primary Clock Skew Within a Device	MachXO3L/LF-1300	—	867	—	897	ps
		MachXO3L/LF-2100	—	867	—	897	ps
		MachXO3L/LF-4300	—	865	—	892	ps
		MachXO3L/LF-6900	—	902	—	942	ps
		MachXO3L/LF-9400	—	908	—	950	ps
Edge Clock							
$f_{MAX_EDGE}^7$	Frequency for Edge Clock	MachXO3L/LF	—	400	—	333	MHz
Pin-LUT-Pin Propagation Delay							
t_{PD}	Best case propagation delay through one LUT-4	All MachXO3L/LF devices	—	6.72	—	6.96	ns
General I/O Pin Parameters (Using Primary Clock without PLL)							
t_{CO}	Clock to Output - PIO Output Register	MachXO3L/LF-1300	—	7.46	—	7.66	ns
		MachXO3L/LF-2100	—	7.46	—	7.66	ns
		MachXO3L/LF-4300	—	7.51	—	7.71	ns
		MachXO3L/LF-6900	—	7.54	—	7.75	ns
		MachXO3L/LF-9400	—	7.53	—	7.83	ns
t_{SU}	Clock to Data Setup - PIO Input Register	MachXO3L/LF-1300	-0.20	—	-0.20	—	ns
		MachXO3L/LF-2100	-0.20	—	-0.20	—	ns
		MachXO3L/LF-4300	-0.23	—	-0.23	—	ns
		MachXO3L/LF-6900	-0.23	—	-0.23	—	ns
		MachXO3L/LF-9400	-0.24	—	-0.24	—	ns
t_H	Clock to Data Hold - PIO Input Register	MachXO3L/LF-1300	1.89	—	2.13	—	ns
		MachXO3L/LF-2100	1.89	—	2.13	—	ns
		MachXO3L/LF-4300	1.94	—	2.18	—	ns
		MachXO3L/LF-6900	1.98	—	2.23	—	ns
		MachXO3L/LF-9400	1.99	—	2.24	—	ns
t_{SU_DEL}	Clock to Data Setup - PIO Input Register with Data Input Delay	MachXO3L/LF-1300	1.61	—	1.76	—	ns
		MachXO3L/LF-2100	1.61	—	1.76	—	ns
		MachXO3L/LF-4300	1.66	—	1.81	—	ns
		MachXO3L/LF-6900	1.53	—	1.67	—	ns
		MachXO3L/LF-9400	1.65	—	1.80	—	ns
t_{H_DEL}	Clock to Data Hold - PIO Input Register with Input Data Delay	MachXO3L/LF-1300	-0.23	—	-0.23	—	ns
		MachXO3L/LF-2100	-0.23	—	-0.23	—	ns
		MachXO3L/LF-4300	-0.25	—	-0.25	—	ns
		MachXO3L/LF-6900	-0.21	—	-0.21	—	ns
		MachXO3L/LF-9400	-0.24	—	-0.24	—	ns
f_{MAX_IO}	Clock Frequency of I/O and PFU Register	All MachXO3L/LF devices	—	388	—	323	MHz

Parameter	Description	Device	-6		-5		Units
			Min.	Max.	Min.	Max.	
General I/O Pin Parameters (Using Edge Clock without PLL)							
t _{COE}	Clock to Output - PIO Output Register	MachXO3L/LF-1300	—	7.53	—	7.76	ns
		MachXO3L/LF-2100	—	7.53	—	7.76	ns
		MachXO3L/LF-4300	—	7.45	—	7.68	ns
		MachXO3L/LF-6900	—	7.53	—	7.76	ns
		MachXO3L/LF-9400	—	8.93	—	9.35	ns
t _{SUE}	Clock to Data Setup - PIO Input Register	MachXO3L/LF-1300	-0.19	—	-0.19	—	ns
		MachXO3L/LF-2100	-0.19	—	-0.19	—	ns
		MachXO3L/LF-4300	-0.16	—	-0.16	—	ns
		MachXO3L/LF-6900	-0.19	—	-0.19	—	ns
		MachXO3L/LF-9400	-0.20	—	-0.20	—	ns
t _{HE}	Clock to Data Hold - PIO Input Register	MachXO3L/LF-1300	1.97	—	2.24	—	ns
		MachXO3L/LF-2100	1.97	—	2.24	—	ns
		MachXO3L/LF-4300	1.89	—	2.16	—	ns
		MachXO3L/LF-6900	1.97	—	2.24	—	ns
		MachXO3L/LF-9400	1.98	—	2.25	—	ns
t _{SU_DELE}	Clock to Data Setup - PIO Input Register with Data Input Delay	MachXO3L/LF-1300	1.56	—	1.69	—	ns
		MachXO3L/LF-2100	1.56	—	1.69	—	ns
		MachXO3L/LF-4300	1.74	—	1.88	—	ns
		MachXO3L/LF-6900	1.66	—	1.81	—	ns
		MachXO3L/LF-9400	1.71	—	1.85	—	ns
t _{H_DELE}	Clock to Data Hold - PIO Input Register with Input Data Delay	MachXO3L/LF-1300	-0.23	—	-0.23	—	ns
		MachXO3L/LF-2100	-0.23	—	-0.23	—	ns
		MachXO3L/LF-4300	-0.34	—	-0.34	—	ns
		MachXO3L/LF-6900	-0.29	—	-0.29	—	ns
		MachXO3L/LF-9400	-0.30	—	-0.30	—	ns
General I/O Pin Parameters (Using Primary Clock with PLL)							
t _{COPLL}	Clock to Output - PIO Output Register	MachXO3L/LF-1300	—	5.98	—	6.01	ns
		MachXO3L/LF-2100	—	5.98	—	6.01	ns
		MachXO3L/LF-4300	—	5.99	—	6.02	ns
		MachXO3L/LF-6900	—	6.02	—	6.06	ns
		MachXO3L/LF-9400	—	5.55	—	6.13	ns
t _{SUPLL}	Clock to Data Setup - PIO Input Register	MachXO3L/LF-1300	0.36	—	0.36	—	ns
		MachXO3L/LF-2100	0.36	—	0.36	—	ns
		MachXO3L/LF-4300	0.35	—	0.35	—	ns
		MachXO3L/LF-6900	0.34	—	0.34	—	ns
		MachXO3L/LF-9400	0.33	—	0.33	—	ns
t _{HPLL}	Clock to Data Hold - PIO Input Register	MachXO3L/LF-1300	0.42	—	0.49	—	ns
		MachXO3L/LF-2100	0.42	—	0.49	—	ns
		MachXO3L/LF-4300	0.43	—	0.50	—	ns
		MachXO3L/LF-6900	0.46	—	0.54	—	ns
		MachXO3L/LF-9400	0.47	—	0.55	—	ns

Parameter	Description	Device	-6		-5		Units
			Min.	Max.	Min.	Max.	
t _{SU_DELPLL}	Clock to Data Setup - PIO Input Register with Data Input Delay	MachXO3L/LF-1300	2.87	—	3.18	—	ns
		MachXO3L/LF-2100	2.87	—	3.18	—	ns
		MachXO3L/LF-4300	2.96	—	3.28	—	ns
		MachXO3L/LF-6900	3.05	—	3.35	—	ns
		MachXO3L/LF-9400	3.06	—	3.37	—	ns
t _{H_DELPLL}	Clock to Data Hold - PIO Input Register with Input Data Delay	MachXO3L/LF-1300	-0.83	—	-0.83	—	ns
		MachXO3L/LF-2100	-0.83	—	-0.83	—	ns
		MachXO3L/LF-4300	-0.87	—	-0.87	—	ns
		MachXO3L/LF-6900	-0.91	—	-0.91	—	ns
		MachXO3L/LF-9400	-0.93	—	-0.93	—	ns

Parameter	Description	Device	-6		-5		Units
			Min.	Max.	Min.	Max.	
Generic DDRX4 Outputs with Clock and Data Centered at Pin Using PCLK Pin for Clock Input – GDDR4_TX.ECLK.Centered^{8,9}							
t _{DVB}	Output Data Valid Before CLK Output	MachXO3L/LF devices, top side only	0.455	—	0.570	—	ns
t _{DVA}	Output Data Valid After CLK Output		0.455	—	0.570	—	ns
f _{DATA}	DDR4 Serial Output Data Speed		—	800	—	630	Mbps
f _{DDR4}	DDR4 ECLK Frequency (minimum limited by PLL)		—	400	—	315	MHz
f _{SCLK}	SCLK Frequency		—	100	—	79	MHz
7:1 LVDS Outputs – GDDR71_TX.ECLK.7:1^{8,9}							
t _{DIB}	Output Data Invalid Before CLK Output	MachXO3L/LF devices, top side only	—	0.160	—	0.180	ns
t _{DIA}	Output Data Invalid After CLK Output		—	0.160	—	0.180	ns
f _{DATA}	DDR71 Serial Output Data Speed		—	756	—	630	Mbps
f _{DDR71}	DDR71 ECLK Frequency		—	378	—	315	MHz
f _{CLKOUT}	7:1 Output Clock Frequency (SCLK) (minimum limited by PLL)		—	108	—	90	MHz
MIPI D-PHY Outputs with Clock and Data Centered at Pin Using PCLK Pin for Clock Input - GDDR4_TX.ECLK.Centered^{10,11,12}							
t _{DVB}	Output Data Valid Before CLK Output	All MachXO3L/LF devices, top side only	0.200	—	0.200	—	UI
t _{DVA}	Output Data Valid After CLK Output		0.200	—	0.200	—	UI
f _{DATA} ¹⁴	MIPI D-PHY Output Data Speed		—	900	—	900	Mbps
f _{DDR4} ¹⁴	MIPI D-PHY ECLK Frequency (minimum limited by PLL)		—	450	—	450	MHz
f _{SCLK} ¹⁴	SCLK Frequency		—	112.5	—	112.5	MHz

1. Exact performance may vary with device and design implementation. Commercial timing numbers are shown at 85 °C and 1.14 V. Other operating conditions, including industrial, can be extracted from the Diamond software.
2. General I/O timing numbers based on LVCMOS 2.5, 8 mA, 0pF load, fast slew rate.
3. Generic DDR timing numbers based on LVDS I/O (for input, output, and clock ports).
4. 7:1 LVDS (GDDR71) uses the LVDS I/O standard (for input, output, and clock ports).
5. For Generic DDRX1 mode t_{SU} = t_{HO} = (t_{DVE} - t_{DVA} - 0.03 ns)/2.
6. The t_{SU_DEL} and t_{H_DEL} values use the SCLK_ZERHOLD default step size. Each step is 105 ps (-6), 113 ps (-5), 120 ps (-4).
7. This number for general purpose usage. Duty cycle tolerance is +/-10%.
8. Duty cycle is +/- 5% for system usage.
9. Performance is calculated with 0.225 UI.
10. Performance is calculated with 0.20 UI.
11. Performance for Industrial devices are only supported with VCC between 1.16 V to 1.24 V.
12. Performance for Industrial devices and -5 devices are not modeled in the Diamond design tool.
13. The above timing numbers are generated using the Diamond design tool. Exact performance may vary with the device selected.
14. Above 800 Mbps is only supported with WLCSP and csfBGA packages
15. Between 800 Mbps to 900 Mbps:
 - a. VIDTH exceeds the MIPI D-PHY Input DC Conditions Table 3-4 and can be calculated with the equation t_{SU} or t_H = -0.0005*VIDTH + 0.3284
 - b. Example calculations
 - i. t_{SU} and t_{HO} = 0.28 with VIDTH = 100 mV
 - ii. t_{SU} and t_{HO} = 0.25 with VIDTH = 170 mV
 - iii. t_{SU} and t_{HO} = 0.20 with VIDTH = 270 mV

	MachXO3L/LF-2100					
	WLCSP49	CSFBGA121	CSFBGA256	CSFBGA324	CABGA256	CABGA324
General Purpose IO per Bank						
Bank 0	19	24	50	71	50	71
Bank 1	0	26	52	62	52	68
Bank 2	13	26	52	72	52	72
Bank 3	0	7	16	22	16	24
Bank 4	0	7	16	14	16	16
Bank 5	6	10	20	27	20	28
Total General Purpose Single Ended IO	38	100	206	268	206	279
Differential IO per Bank						
Bank 0	10	12	25	36	25	36
Bank 1	0	13	26	30	26	34
Bank 2	6	13	26	36	26	36
Bank 3	0	3	8	10	8	12
Bank 4	0	3	8	6	8	8
Bank 5	3	5	10	13	10	14
Total General Purpose Differential IO	19	49	103	131	103	140
Dual Function IO	25	33	33	37	33	37
Number 7:1 or 8:1 Gearboxes						
Number of 7:1 or 8:1 Output Gearbox Available (Bank 0)	5	7	14	18	14	18
Number of 7:1 or 8:1 Input Gearbox Available (Bank 2)	6	13	14	18	14	18
High-speed Differential Outputs						
Bank 0	5	7	14	18	14	18
VCCIO Pins						
Bank 0	2	1	4	4	4	4
Bank 1	0	1	3	4	4	4
Bank 2	1	1	4	4	4	4
Bank 3	0	1	2	2	1	2
Bank 4	0	1	2	2	2	2
Bank 5	1	1	2	2	1	2
VCC	2	4	8	8	8	10
GND	4	10	24	16	24	16
NC	0	0	0	13	1	0
Reserved for Configuration	1	1	1	1	1	1
Total Count of Bonded Pins	49	121	256	324	256	324

	MachXO3L/LF-4300						
	WLCSP81	CSFBGA121	CSFBGA256	CSFBGA324	CABGA256	CABGA324	CABGA400
General Purpose IO per Bank							
Bank 0	29	24	50	71	50	71	83
Bank 1	0	26	52	62	52	68	84
Bank 2	20	26	52	72	52	72	84
Bank 3	7	7	16	22	16	24	28
Bank 4	0	7	16	14	16	16	24
Bank 5	7	10	20	27	20	28	32
Total General Purpose Single Ended IO	63	100	206	268	206	279	335
Differential IO per Bank							
Bank 0	15	12	25	36	25	36	42
Bank 1	0	13	26	30	26	34	42
Bank 2	10	13	26	36	26	36	42
Bank 3	3	3	8	10	8	12	14
Bank 4	0	3	8	6	8	8	12
Bank 5	3	5	10	13	10	14	16
Total General Purpose Differential IO	31	49	103	131	103	140	168
Dual Function IO	25	37	37	37	37	37	37
Number 7:1 or 8:1 Gearboxes							
Number of 7:1 or 8:1 Output Gearbox Available (Bank 0)	10	7	18	18	18	18	21
Number of 7:1 or 8:1 Input Gearbox Available (Bank 2)	10	13	18	18	18	18	21
High-speed Differential Outputs							
Bank 0	10	7	18	18	18	18	21
VCCIO Pins							
Bank 0	3	1	4	4	4	4	5
Bank 1	0	1	3	4	4	4	5
Bank 2	2	1	4	4	4	4	5
Bank 3	1	1	2	2	1	2	2
Bank 4	0	1	2	2	2	2	2
Bank 5	1	1	2	2	1	2	2
VCC	4	4	8	8	8	10	10
GND	6	10	24	16	24	16	33
NC	0	0	0	13	1	0	0
Reserved for Configuration	1	1	1	1	1	1	1
Total Count of Bonded Pins	81	121	256	324	256	324	400